

April 1988 Revised October 2000

74F543

Octal Registered Transceiver

General Description

The F543 octal transceiver contains two sets of D-type latches for temporary storage of data flowing in either direction. Separate Latch Enable and Output Enable inputs are provided for each register to permit independent control of inputting and outputting in either direction of data flow. The A outputs are guaranteed to sink 24 mA while the B outputs are rated for 64 mA.

Features

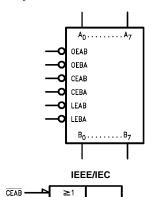
- 8-bit octal transceiver
- Back-to-back registers for storage
- Separate controls for data flow in each direction
- A outputs sink 24 mA
- B outputs sink 64 mA

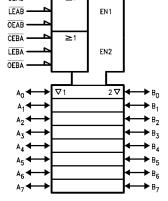
Ordering Code:

Order Number	Package Number	Package Description
74F543SC	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74F543MSA	MSA24	24-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
74F543PC	N24A	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-011, 0.600 Wide
74F543SPC	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

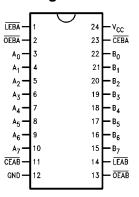
Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbols





Connection Diagram



Unit Loading/Fan Out

Pin Names	Description	U.L.	Input I _{IH} /I _{IL}	
Pin Names	Description	HIGH/LOW	Output I _{OH} /I _{OL}	
OEAB	A-to-B Output Enable Input (Active LOW)	1.0/1.0	20 μA/-0.6 mA	
OEBA	B-to-A Output Enable Input (Active LOW)	1.0/1.0	20 μA/-0.6 mA	
CEAB	A-to-B Enable Input (Active LOW)	1.0/2.0	20 μA/–1.2 mA	
CEBA	B-to-A Enable Input (Active LOW)	1.0/2.0	20 μA/–1.2 mA	
LEAB	A-to-B Latch Enable Input (Active LOW)	1.0/1.0	20 μA/-0.6 mA	
LEBA	B-to-A Latch Enable Input (Active LOW)	1.0/1.0	20 μA/-0.6 mA	
A ₀ -A ₇	A-to-B Data Inputs or	3.5/1.083	70 μΑ/–650 μΑ	
	B-to-A 3-STATE Outputs	150/40 (33.8)	-3 mA/24 mA (20 mA)	
B ₀ -B ₇	B-to-A Data Inputs or	3.5/1.083	70 μΑ/–650 μΑ	
	A-to-B 3-STATE Outputs	600/106.6 (80)	-12 mA/64 mA (48 mA)	

Functional Description

The F543 contains two sets of eight D-type latches, with separate input and output controls for each set. For data flow from A to B, for example, the A-to-B Enable $(\overline{\text{CEAB}})$ input must be LOW in order to enter data from A_0-A_7 or take data from B_0-B_7 , as indicated in the Data I/O Control Table. With $\overline{\text{CEAB}}$ LOW, a LOW signal on the A-to-B Latch Enable ($\overline{\text{LEAB}}$) input makes the A-to-B latches transparent; a subsequent LOW-to-HIGH transition of the $\overline{\text{LEAB}}$ signal puts the A latches in the storage mode and their outputs no longer change with the A inputs. With $\overline{\text{CEAB}}$ and $\overline{\text{OEAB}}$ both LOW, the 3-STATE B output buffers are active and reflect the data present at the output of the A latches. Control of data flow from B to A is similar, but using the $\overline{\text{CEBA}}$, $\overline{\text{LEBA}}$ and $\overline{\text{OEBA}}$ inputs.

Data I/O Control Table

	Inputs		Latch	Output	
CEAB	LEAB	OEAB	Status	Buffers	
Н	Х	Х	Latched	High Z	
Х	Н	Χ	Latched	_	
L	L	Χ	Transparent	_	
Х	Χ	Н	_	High Z	
L	Х	L	_	Driving	

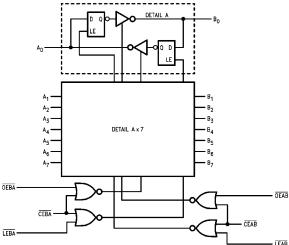
H = HIGH Voltage Level

L = LOW Voltage Level

X = Immaterial

A-to-B data flow shown; B-to-A flow control is the same, except using $\overline{\text{CEBA}}, \overline{\text{LEBA}}$ and $\overline{\text{OEBA}}$

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings(Note 1)

-65°C to +150°C Storage Temperature Ambient Temperature under Bias -55°C to +125°C

 $-55^{\circ}C$ to $+150^{\circ}C$ Junction Temperature under Bias V_{CC} Pin Potential to Ground Pin -0.5V to +7.0V

Input Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output

in HIGH State (with $V_{CC} = 0V$)

Standard Output -0.5V to V_{CC} 3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA)

Recommended Operating Conditions

Free Air Ambient Temperature 0°C to +70°C Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

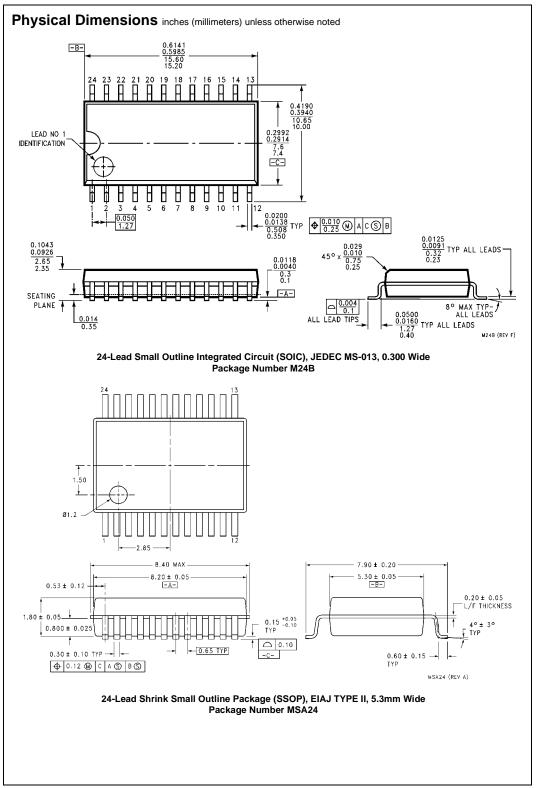
Symbol	Parameter		Min	Тур	Max	Units	V _{CC}	Conditions
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal
V _{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal
V _{CD}	Input Clamp Diode Voltage				-1.2	V	Min	I _{IN} = -18 mA
V _{OH}	Output HIGH Voltage	10% V _{CC}	2.5					$I_{OH} = -1 \text{ mA } (A_n)$
		10% V _{CC}	2.4					$I_{OH} = -3 \text{ mA } (A_n, B_n)$
		5% V _{CC}	2.7			V	Min	$I_{OH} = -1 \text{ mA } (A_n)$
		5% V _{CC}	2.7					$I_{OH} = -3 \text{ mA } (A_n, B_n)$
		10% V _{CC}	2.0					$I_{OH} = -15 \text{ mA } (B_n)$
V _{OL}	Output LOW	10% V _{CC}			0.5	V	Min	$I_{OL} = 24 \text{ mA } (A_n)$
	Voltage	10% V _{CC}			0.55			$I_{OL} = 64 \text{ mA } (B_n)$
I _{IH}	Input HIGH Current				5.0	μΑ	Max	$V_{IN} = 2.7V$
I _{BVI}	Input HIGH Current				7.0			(OEAB, OEBA, LEAB,
	Breakdown Test				7.0	μΑ	Max	LEBA, CEAB, CEBA)
I _{BVIT}	Input HIGH Current				0.5	mA	Max	V 55V (A B)
	Breakdown (I/O)				0.5	mA	IVIAX	$V_{IN} = 5.5V (A_n, B_n)$
I _{CEX}	Output HIGH				50		Max	V V
	Leakage Current				50	μА	IVIAX	$V_{OUT} = V_{CC}$
V _{ID}	Input Leakage		4.75			V	0.0	I _{ID} = 1.9 μA
	Test		4.75			•	0.0	All Other Pins Grounded
I _{OD}	Output Leakage				3.75	μА	μA 0.0	$V_{IOD} = 150 \text{ mV}$
	Circuit Current				0.70	μιτ	0.0	All Other Pins Grounded
I _{IL}	Input LOW Current				-0.6	mA		$V_{IN} = 0.5V (\overline{OEAB}, \overline{OEBA})$
				-1.2	Max		$V_{IN} = 0.5V (\overline{CEAB}, \overline{CEBA})$	
I _{IH} + I _{OZH}	Output Leakage Curren	t			70	μΑ	Max	$V_{OUT} = 2.7V (A_n, B_n)$
I _{IL} + I _{OZL}	Output Leakage Curren	t			-650	μΑ	Max	$V_{OUT} = 0.5V (A_n, B_n)$
Ios	Output Short-Circuit Current		-60		-150	mA Max	May	$V_{OUT} = 0V (A_n)$
			-100		-225		IVIAX	$V_{OUT} = 0V (B_n)$
I _{ZZ}	Bus Drainage Test				500	μА	0.0V	$V_{OUT} = 5.25V (A_n, B_n)$
I _{CCH}	Power Supply Current			67	100	mA	Max	V _O = HIGH
I _{CCL}	Power Supply Current			83	125	mA	Max	$V_O = LOW$
I _{CCZ}	Power Supply Current			83	125	mA	Max	V _O = HIGH Z

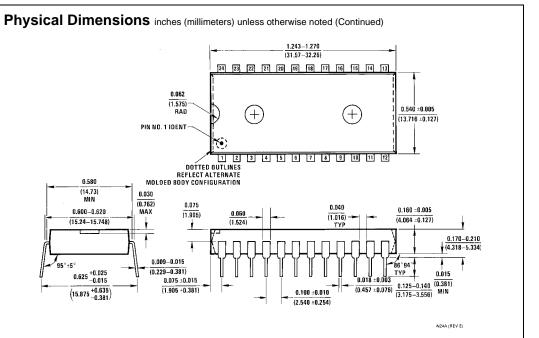
AC Electrical Characteristics

Symbol	Parameter		$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$		$T_A = 0$ °C to +70°C $C_L = 50 \text{ pF}$		Units
		Min	Тур	Max	Min	Max	
t _{PLH}	Propagation Delay	3.0	5.5	7.5	3.0	8.5	
t _{PHL}	Transparent Mode	3.0	5.0	6.5	3.0	7.5	ns
	A_n to B_n or B_n to A_n						
t _{PLH}	Propagation Delay	4.5	8.5	11.0	4.5	12.5	ns
t _{PHL}	LEBA to A _n	4.5	8.5	11.0	4.5	12.5	115
t _{PLH}	Propagation Delay	4.5	8.5	11.0	4.5	12.5	ns
t _{PHL}	LEAB to B _n	4.5	8.5	11.0	4.5	12.5	115
t _{PZH}	Output Enable Time						
t_{PZL}	OEBA or OEAB to A _n or B _n	3.0	7.0	9.0	3.0	10.0	
	CEBA or CEAB to A _n or B _n	4.0	7.5	10.5	4.0	12.0	ns
t _{PHZ}	Output Disable Time						115
t _{PLZ}	OEBA or OEAB to A _n or B _n	1.0	6.0	8.0	1.0	9.0	
	CEBA or CEAB to A _n or B _n	2.5	5.5	10.5	2.5	11.5	

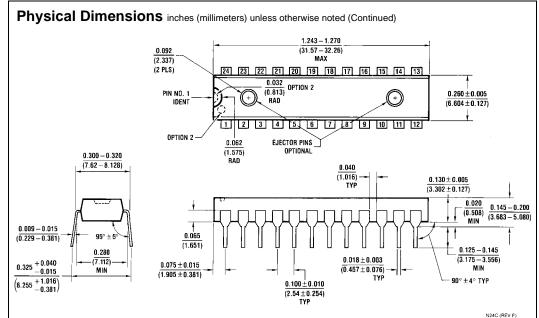
AC Operating Requirements

Symbol	Parameter		+25°C - +5.0V	T _A = 0°C	Units	
		Min	Max	Min	Max	1
t _S (H)	Setup Time, HIGH or LOW	3.0		3.5		
t _S (L)	A _n or B _n to LEBA or LEAB	3.0		3.5		ns
t _H (H)	Hold Time, HIGH or LOW	3.0		3.5		115
t _H (L)	A _n or B _n to LEBA or LEAB	3.0		3.5		
t _W (L)	Latch Enable, B to A or	8.0		9.0		ne
	B to A Pulse Width, LOW	6.0		9.0		ns





24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-011, 0.600 Wide Package Number N24A



24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N24C

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